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| Substitute for form 1449A/PTO<br><b>INFORMATION DISCLOSURE<br/>STATEMENT BY APPLICANT</b><br>(use as many sheets as necessary) |   |                   |   | <b>Complete if Known</b> |  |
| Application Number   |   | 10/083,241        |   |                          |  |
| Filing Date  |   | February 25, 2002 |   |                          |  |
| First Named Inventor   |   | Yervant Zorian    |   |                          |  |
| Art Unit   |   | 2133              |   |                          |  |
| Examiner Name  |   | Ton, David        |   |                          |  |
| Attorney Docket Number   |   | 4640P006          |   |                          |  |
| Sheet  | 1 | of                | 2 |                          |  |

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|                       |              | US-                            |   |  |   |
|                       |              | US-                            |   |  |   |
|                       |              | US-                            |   |  |   |

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| Examiner<br>Initials*    | Cite<br>No.† | Foreign Patent Document |                                 | Publication Date<br>MM-DD-YYYY | Name of Patentee or<br>Applicant of Cited Document | Pages, Columns, Lines,<br>Where Relevant Passages<br>or Relevant Figures Appear |
|                          |              | Country Code*           | Number* - Kind Code* (if known) |                                |  |   |
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| Examiner<br>Signature |  | Date<br>Considered | 11/20/2005 |
|-----------------------|---|--------------------|------------|

\*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication.

†Applicant's unique citation designation number (optional). \*See Kinds Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov) or MPEP 901.04. \*Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). \*For Japanese patent documents, the indication of the year of reign of the Emperor must precede the serial number of the patent document. \*Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 18 if possible. \*Applicant is to place a check mark here if English language Translation is attached.

Based on PTO/SB/08A (08-03) as modified by Blakely, Solakoff, Taylor & Zafman (wr) 08/11/2003.

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| <b>Substitute for form 43A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> |  |  |  | <b>Complete if Known</b> |                   |
|  |  |  |  | Application Number       | 10/083,241        |
| <b>Sheet 2 of 2</b>  |  |  |  | Filing Date              | February 25, 2002 |
|  |  |  |  | First Named Inventor     | Yervant Zorian    |
|  |  |  |  | Art Unit                 | 2133              |
|  |  |  |  | Examiner Name            | Ton, David        |
|  |  |  |  | Attorney Docket Number   | 4640P006          |

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| Examiner Initials*              | Cite No.† | Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published. | T† |
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|--------------------|------------------|-----------------|------------|
| Examiner Signature | <i>David Ton</i> | Date Considered | 11/20/2005 |
|--------------------|------------------|-----------------|------------|

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